



DEFENSE LOGISTICS AGENCY
LAND AND MARITIME
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October 26, 2020

Mr. Joseph Gustafson
Quality Manager
Micross Components Orlando (MCO)
7725 N. Orange Blossom Trail
Orlando, FL 32810

Dear Mr. Gustafson:

Re: Laboratory Suitability MIL-STD-750; FSC 5962; VQH-21-035596, Control Number: 073172
& 074177

Based on a review of your MIL-STD-750 procedures, submitted 06/18/2020, a satisfactory confidence level of Laboratory Suitability has been demonstrated. Micross is granted Laboratory Suitability for the facilities, test methods, and conditions shown on the enclosure. This Laboratory Suitability supersedes the previous Laboratory Suitability, DLA Land and Maritime-VQH-21-035596. This Laboratory Suitability also covers Micross's Commercial Laboratory Suitability. All testing covered by this approval must be performed in accordance with MIL-PRF-38534 and MIL-STD-750 test methods.

The standard reporting period is from 1 January through 30 June and from 1 July to 31 December each year and is due within one month after the reporting period has ended.

Micross shall notify DLA Land and Maritime-VQH immediately after learning of a potential issuance of a GIDEP alert, problem advisory or major quality/reliability problem on their military products utilizing the test methods on the attached enclosure. Failure to provide notification to the DLA Land and Maritime Qualifying Activity may be grounds for removal from the Commercial Laboratory Suitability Listing.

This Laboratory Suitability is subject to the policies, procedures, and conditions of the Defense Standardization Program, as published in DoD 4120.24-M and SD-6. This Laboratory Suitability is valid until terminated by written notice from DLA Land and Maritime-VQH. If warranted, it may be withdrawn by DLA Land and Maritime-VQH at any time. Any facility listed on the enclosure is subject to an audit by the Qualifying Activity with a minimum notice.

Sincerely,

RICHARD J. BARKER
Chief
Hybrid Devices Branch

cc:
DLA Land and Maritime-VQH (Sema Kazemi)

Enclosure to DLA Land and Maritime-VQH-21-035596

TEST	METHOD/CONDITION	MICROSS ORLANDO	OUTSOURCE LAB
Moisture Resistance	1004	X	HRM
Steady State Life Test	1005/A,B,C,D,E,F	X	HRM
Stabilization Bake	1008/A,B,C,D,E,F	X	HRM, MMT
Salt Atmosphere	1009/A,B,C,D	X	HRM
Temperature Cycling	1010/A,B,C	X	HRM, MMT
Temperature Cycling	*1051/C	X	
Thermal Shock	1011/A,B,C	X	HRM
Seal	1014/A1,A2,B1,B2,B2/B1,C1	X	
Seal	1014/A1,A2,C1		HRM
Seal	1014/B1,C1		MMT
Burn-in	1015/A,B,C,D,E,F	X	HRM
Burn-In (Power MOSFET) Gate Bias (IGBT)	*1042/B	X	
Burn-in (Power), Reverse Bias (Zener, Rectifier)	*1038/A	X	
Burn-in Steady State Life (Transistor-Signal, Transistor Power)	*1039/B	X	
Burn-in Steady State Life (IGBT, MOSFET-Power)	*1042/A	X	
Burn-in Steady State Life, (Diode-Zener, Diode-Power Rectifier)	*1038/B	X	
Burn-in Steady State Life, (SCR)	*1040/B	X	
Internal Water Vapor Content	1018		AAL, EAG, ORS
Constant Acceleration	2001/A,B,C,D,E	X	HRM, MMT
Constant Acceleration	*2006/A	X	
Mechanical Shock	2002/B	X	HRM
Mechanical Shock	*2016	X	
Solderability	2003	X	HRM
Lead Integrity	2004/A,B1,B2,D	X	HRM
Vibration, Variable Frequency	2007/A	X	HRM
External Visual	2009	X	HRM, MMT

TEST	METHOD/CONDITION	MICROSS ORLANDO	OUTSOURCE LAB
Internal Visual	2010/A,B	X	MMT
Bond Strength	2011/D	X	HRM, MMT
Radiography	2012	X	MMT
Internal Visual for DPA	2013	X	
Internal Visual & Mechanical	2014	X	MMT
Pre-Cap Visual, Power MOSFET's	*2069	X	
Pre-Cap Visual, Discrete	*2070	X	
Visual Inspection for Transistor	*2072	X	
Visual Inspection for Diode	*2073	X	
Resistance to Solvents	2015	X	HRM
Physical Dimensions	2016	X	HRM
Internal Visual (Hybrid)	2017	X	MMT
SEM	2018	X	HRL
SEM	*2077	X	
Die Shear Strength	2019	X	HRM, MMT
PIND	2020/A,B	X	HRM, MMT
Glassivation Integrity	2021/B	X	
Nondestructive Bond Pull	2023	X	HRM, MMT
Lid torque	2024		HRM
Adhesion of Lead Finish	2025	X	HRM
Substrate Attach Strength	2027		HRM
Visual Inspection	2032	X	MMT
Resistance to Soldering Heat	2036/A,B,I,J,K		HRM
ESDS Classification	3015		HRM
Wafer Lot Acceptance	5007		HRL
Electrical Test	Per MIL-STD-883 paragraph 4.5 and device spec.	X	HRM
Surge Current	*4066/A,B	X	
High Temperature Reverse Bias (HTRB)	*1039/A	X	
Hot Solder Dip			MCH
Marking		X	MMT
Assembly Subcontractors	MIL-PRF-38534, Class H, MIL-PRF-38535, Class Q	X	MMT

*MIL-STD-750 Test Methods

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